

## Randomized Benchmarking Using Nondestructive Readout in a Two-Dimensional Atom Array

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Neutral atoms are a promising platform for scalable quantum computing, however, prior demonstration of high fidelity gates or low-loss readout methods have employed restricted numbers of qubits. Using randomized benchmarking of microwave-driven single-qubit gates, we demonstrate average gate errors of  $7(2) \times 10^{-5}$  on a 225 site atom array using conventional, destructive readout. We further demonstrate a factor of 1.7 suppression of the primary measurement errors via low-loss, nondestructive, and state-selective readout on 49 sites while achieving gate errors of  $2(9) \times 10^{-4}$ .

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Neutral atoms have emerged as a competitive platform for scalable quantum computing [1–3], using arrays of optical tweezers or optical lattices to create deterministically loaded, defect-free qubit registers of atoms in up to three dimensions [4–8] in arrays with over 1000 sites [9]. Interactions between highly excited Rydberg states can be exploited to perform high-fidelity two- [10–16] or multi-qubit gate operations [14,17], with the ability to realize complex connectivities using movable tweezers [18]. As well as enabling recent demonstrations of quantum algorithms [18,19], this same platform can be exploited for quantum simulation [20–22] or analog quantum computation to address practical optimization problems [23,24].

An essential requirement for future fault-tolerant scaling is the ability to perform gate operations below the error threshold [25–27]. One approach to measuring the average gate errors is randomized benchmarking, originally proposed for trapped ions [28,29] and later adapted to a range of different hardware platforms [30–32]. This method averages performance over random strings of Clifford gates to extract both gate and readout errors. Randomized benchmarking has been used to characterize microwave-driven single-qubit gates in optical lattices [32–34] and tweezer arrays [35,36] of neutral atoms, but to date has only been demonstrated to exceed this threshold for a subset of 16 atoms [36].

A second requirement for future scaling is the ability to perform scalable and high-fidelity nondestructive readout (NDRO) to suppress measurement errors arising from the typical destructive readout scheme of ejecting atoms in

qubit state  $|1\rangle$  prior to imaging which cannot distinguish against atom loss during computation [37]. Significant progress has been demonstrated for NDRO of up to a few qubits using selective fluorescence in free-space [38–41], a high-finesse optical cavity [42–44], and atomic ensembles [45] permitting fast detection on 100  $\mu$ s timescales with fidelities up to 0.999. However, quantum error correction necessitates repeated and parallel NDRO measurements of ancilla qubits in large arrays [46,47], presently only achieved using state-selective forces in a 3D lattice [48].

In this Letter we demonstrate randomized benchmarking combined with a non-destructive readout (NDRO) across a 2D array using a low-loss technique that allows simultaneous measurement of qubit state and presence to allow postselection against loss. First we showcase the capabilities of our experimental platform on a 225 trap site array by performing Clifford group randomized benchmarking with composite microwave (MW) pulses and a conventional, destructive readout process. Then, we implement NDRO on a 49 site array, limited by the available optical dipole trap (ODT) laser power required to create the higher trap depths needed during readout. Using this smaller array, we compare the randomized benchmarking performance obtained with conventional and nondestructive readout techniques. We demonstrate that we can efficiently transfer the atoms between the computational state  $|1\rangle$ , and the stretched state, where the nondestructive measurement takes place, using the NDRO beams. Finally, we discuss the limitations in the present NDRO performance and highlight experimental improvements to further reduce single atom losses. Combining this technique with long vacuum lifetime cryogenic systems [49] and atom sorting [4,5] could allow for the same atoms to be re-used for multiple experimental cycles leading to significantly faster repetition rates. This approach is also compatible with recent demonstration of mid-circuit measurement of

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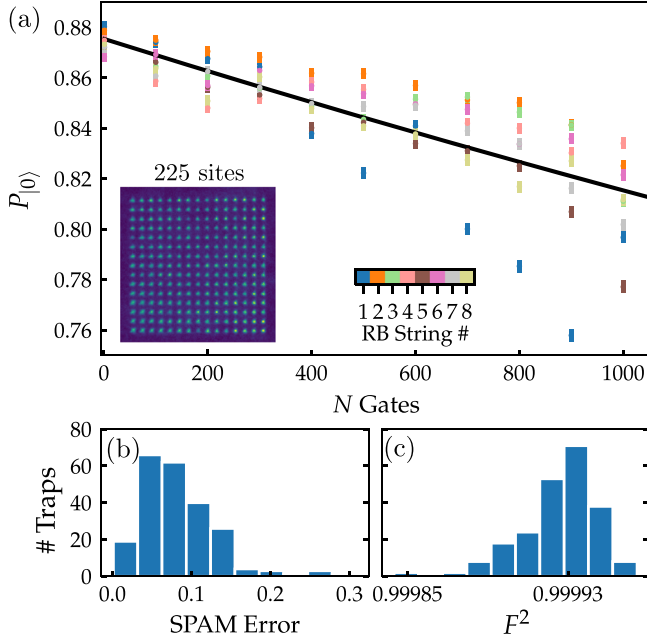


FIG. 2. Randomized benchmarking of 225 trap sites: (a) Array-averaged results from 8 different random gate strings with fit using Eq. (1). Histograms showing the distribution of (b) SPAM errors and (c) average gate fidelities,  $F^2$ , across the array. Error bars represent 1 standard deviation.

pulses equivalent to rotating the coordinate axes in the Bloch sphere. This results in an average area per gate of  $\langle \theta \rangle_{C_1} = 2.95\pi$ .

Using this experimental method, we generate 8 different random gate strings with a maximal length reaching up to  $N = 1000$  gates. After applying the randomized sequence, a final correction pulse is applied to return the qubit to the  $|0\rangle$  state, and the output populations are measured using 150 repeats for each data point. The total time allocated for microwave operations was fixed at 375 ms regardless of the number of gates applied in a given experimental run. The results of the randomized benchmarking on the 225-site array obtained using a destructive readout method are shown in Fig. 2(a) for each of the random gate strings. Error bars show 1 standard deviation. To extract the gate errors, a single fit function is applied to all data points using the equation

$$P_{|0\rangle} = \frac{1}{2} + \frac{1}{2}(1 - d_{\text{SPAM}})(1 - d)^N, \quad (1)$$

where  $N$  is the number of random gates applied,  $d_{\text{SPAM}}$  is the state preparation and measurement error, and  $d$  is the average depolarization error per gate. For this conventional destructive readout approach  $P_{|0\rangle}$  must be additionally scaled by the atom loss probability due to the finite trap lifetime of 9.7(8) s, which is independently measured to be 0.93(1) [53]. The averaged gate fidelity is then obtained from  $F^2 = 1 - d/2$  [35]. Figures 2(b) and 2(c) show the

distribution of SPAM error and fidelity across the array, with an array-averaged gate fidelity of  $\langle F^2 \rangle = 0.99993(2)$  (corresponding to an average error of  $7 \times 10^{-5}$ ) and a maximum value of  $F^2_{\text{max}} = 0.99996(3)$  at a single array site.

These results represent the highest recorded averaged single qubit gate fidelities for any quantum computing platform with over 100 qubits. A lower average microwave single qubit gate error of  $4.7 \pm 1.1 \times 10^{-5}$  has previously only been achieved in  $4 \times 4$  arrays of  $^{87}\text{Rb}$  atoms using magic polarization to suppress differential light shifts [36]. Our numbers are in good agreement with the theory from Ref. [35] which predicts  $\langle F^2 \rangle = 1 - \langle d \rangle / 2 = 1 - [1 - \alpha(\langle t \rangle_{C_1}, T_2^*)] / 2$ , where  $\alpha = 0.5 + 0.5[1 + 0.95(t/T_2^*)^2]^{-3/2}$  describes the loss of coherence due to dephasing [58] and  $\langle t \rangle_{C_1} = \langle \theta \rangle_{C_1} / \Omega$  is the average Clifford gate duration. Using the values above we predict an error of  $4 \times 10^{-5}$ , with additional sources of error likely arising from magnetic field noise or residual phase-noise in the rf electronics.

A consequence of using BB1 pulses is the increased duration for longer gate sequences, which contributes to increased probability of loss due to background collisions and hence the high average SPAM error of 25% due to the inability to distinguish between a real qubit error with an atom left in  $|1\rangle$  at the end of the sequence and an atom being lost during the computation.

To address this issue, we now introduce non-destructive state readout (NDRO) following the approach of [39,40]. Instead of applying a resonant blow-away pulse to remove atoms in  $F = 4$ , we perform a state-selective pulse using  $\sigma^+$  polarized light on the  $D_2 F = 4 \rightarrow F' = 5$  transition, which optically pumps atoms in  $|1\rangle$  into the  $|4, 4\rangle$  stretched-state to enable bright-state imaging on the cycling transition, while atoms in  $|0\rangle$  are unaffected and remain dark. A subsequent imaging step is then performed using standard cooling and repump beams to verify the presence or absence of an atom in either hyperfine state to enable postselection for loss.

In the experiment, NDRO is implemented using a pair of counter-propagating beams oriented along the quantization axis as shown in Fig. 1(a). The beams are operated with a combined intensity equal to the saturation intensity  $I_0 = 1.6 \text{ mW/cm}^2$  and an average detuning of  $\Delta/2\pi = -0.75\Gamma$  from the  $|F = 4, m_F = 4\rangle \rightarrow |F' = 5, m'_F = 5\rangle$  transition. Where  $\Gamma/2\pi = 5.2 \text{ MHz}$  is the excited state linewidth. The beams are operated with a relative frequency difference of 600 kHz to suppress standing-wave interference. As above, light is modulated out of phase with the ODT to suppress ac shifts and heating. The ODT is also polarized along the quantization axis to avoid fictitious magnetic fields [39].

Efficient NDRO requires maximizing the number of photons scattered to provide the maximal separation of bright and dark count rates for high-fidelity state detection, while minimizing losses due to heating on the cycling transition or leakage into  $F = 3$  due to off-resonant scattering from imperfect polarization. We perform initial



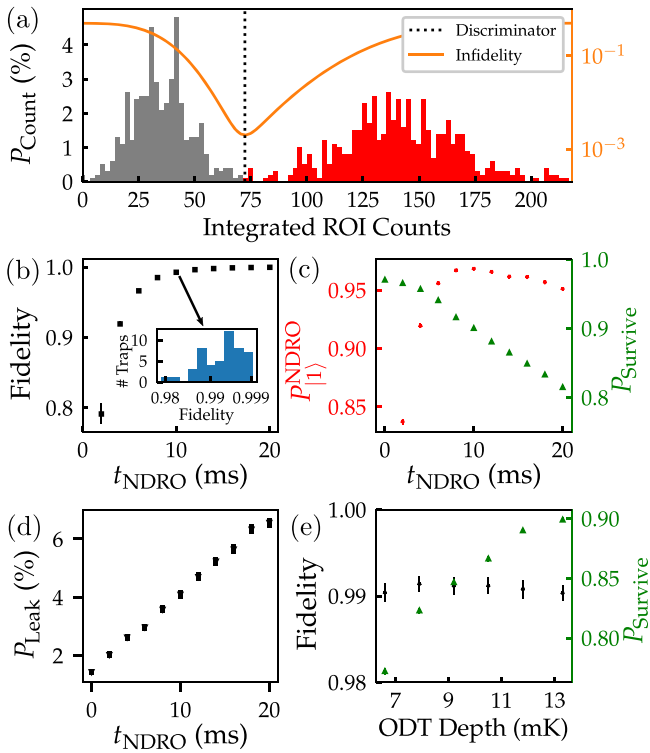


FIG. 3. NDRO characterization on  $7 \times 7$  array at 13.3 mK trap depth. (a) Example NDRO histogram of integrated ROI counts for a single trap at  $t_{\text{NDRO}} = 10$  ms with dashed line showing threshold that maximises detection fidelity. (b) NDRO detection fidelity vs duration, with inset showing distribution across all traps at  $t_{\text{NDRO}} = 10$  ms. (c) NDRO detection ( $P_{|1\rangle}^{\text{NDRO}}$ ) and survival probabilities as a function of  $t_{\text{NDRO}}$ . (d) Leakage probability into  $|F = 3\rangle$  during NDRO. From (b)–(d) we operate at  $t_{\text{NDRO}} = 10$  ms to balance detection fidelity against errors from loss and leakage. (e) Survival and fidelity vs trap depth showing improved survival with trap depth while fidelity remains approximately constant.

optimization of NDRO parameters using a  $7 \times 7$  array, adiabatically ramping the trap to a depth of 13.3 mK for the NDRO stage (limited by the available ODT power) to suppress losses. Figure 3(a) shows an example NDRO histogram obtained for 10 ms imaging duration, with red (gray) denoting counts from atoms initially prepared in the  $|1\rangle(|0\rangle)$  state. From these histograms we determine the threshold value that minimizes false negative or positive errors, from which we can extract the detection fidelity. In Figs. 3(b)–3(d) we present experimental data for NDRO performance as a function of readout time  $t_{\text{NDRO}}$ . Figure 3(b) shows readout fidelity, (c) shows the probability of the atom surviving the readout process  $P_{\text{Survive}}$ , as well as the loss-corrected detection probability,  $P_{|1\rangle}^{\text{NDRO}}$ , defined as the probability of being detected in  $|1\rangle$  given the atom survived. Another important parameter is the impact of leakage into  $F = 3$  during the readout process. To measure the leakage rate, we perform the NDRO sequence

followed by resonant blow away to remove any atoms remaining in  $F = 4$  prior to the final image, with results shown in Fig. 3(d). From these data we choose to operate at  $t_{\text{NDRO}} = 10$  ms, offering a compromise between the requirements with a 0.900(2) NDRO survival probability with a state detection fidelity of 0.9926(6). We obtain an NDRO detection probability  $P_{|1\rangle}^{\text{NDRO}} = 0.968(1)$ , comparable to the measured state preparation fidelity for initializing atoms in the  $|1\rangle$  state, and with a probability of leaking into  $F = 3$  during readout of 4.1(1)%. The current state of the art performance for NDRO detection was reported in [41] with  $99.91 \pm 0.02\%$  detection fidelity and 0.9(2)% detection driven loss for a single Cs atom using an adaptive detection scheme using a single photon counting module.

Finally, we investigate the effect of trap depth on atom retention after NDRO, which improves with increasing trap depth without compromising discriminator fidelity as shown in Fig. 3(e). The final data point corresponds to 13.3 mK trap depth which is the maximum we can achieve for this array size with our current experimental setup, with further improvements expected with more laser power.

We now apply the randomized benchmarking using the same gate sequences as above on the smaller  $7 \times 7$  array with NDRO detection, performing analysis now using the loss-corrected conditional probability  $P_{|1\rangle}^{\text{NDRO}}$  with results shown in Fig. 4. Using this readout scheme we achieve an array averaged fidelity of  $\langle F^2 \rangle = 0.99978(9)$ , in excellent

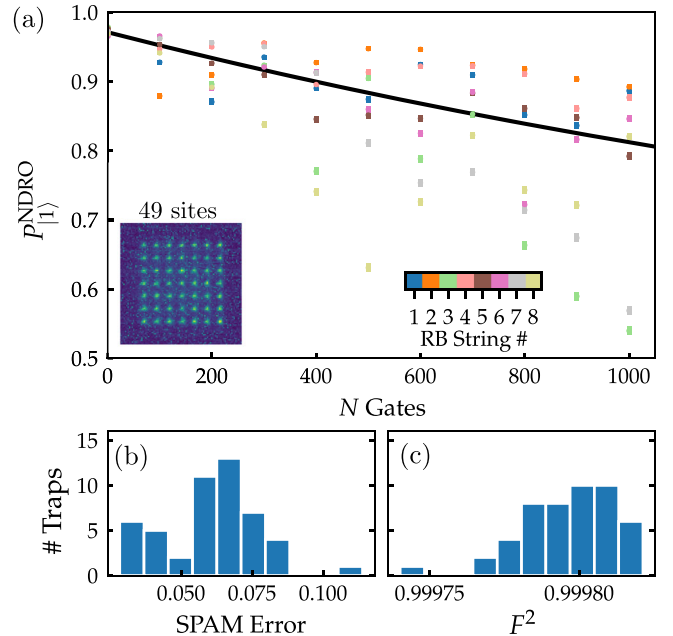


FIG. 4. (a) Randomized benchmarking results for 49 site array readout using NDRO from  $|1\rangle$  state, postselected for survival. The same random gate strings were used as for the 225 site array. Distributions of (b) average gate fidelities and (c) SPAM errors obtained with a fit using Eq. (1).

agreement with the performance obtained in a repeated control measurement using the conventional readout sequence above with  $\langle F^2 \rangle = 0.99\,978(1)$  [53]. The reduction in performance compared to the larger array is attributable to the finite extinction ratio of the ODT acousto-optic modulator meaning the microwave operations are performed at an increased trap depth, increasing the differential AC Stark shifts due to the ODT light from 39 to 211 Hz which results in a reduction of the coherence time for the smaller array  $T_2^* = 12$  ms. The main improvement from the NDRO method comes from a factor of 1.7 reduction in SPAM error compared to the conventional readout with 225 sites. The SPAM error now amounts to  $< 5\%$  as shown in Fig. 4(c). This is due to the removal of false positives corresponding to counting lost atoms as  $|1\rangle$  during the readout process, with the dominant error now the finite state preparation fidelity.

In conclusion, we have demonstrated high fidelity single qubit gate operations with an average error of  $7 \times 10^{-5}$  by performing randomized benchmarking of global microwave pulses on an array with 225 sites using conventional, destructive detection. We have further demonstrated the ability to perform low-loss, nondestructive readout on an array of up to 49 qubits, and used the NDRO method to suppress SPAM errors due to the inability to discriminate against single atom loss. Already these operations are suitable for future fault-tolerant performance, but further improvements are possible using higher microwave powers to reduce the total gate time and considering additional composite or shaped pulse sequences to suppress frequency errors [56]. While previous experiments have achieved faster readout and lower loss for small numbers of qubits  $\lesssim 5$  [39–41], we have demonstrated this NDRO technique can be scaled to larger 2D arrays.

NDRO performance is currently limited by the finite detection efficiency which limits the number of photon counts detected, and the limited trap depth during NDRO. In future, higher fidelity and reduced loss can be obtained by using an electron-multiplied CCD camera offering higher gain and quantum efficiencies  $> 90\%$ , or using a retroreflector to recover photons scattered away from the camera [40], to speed up readout and suppress heating. Similarly, changing to a magic wavelength trap at 935 nm to enable trapping of both ground and excited states [36] both eliminates the requirement for modulating the traps while increasing the effective trap depth from operating closer to resonance, corresponding to approximately 5 times more traps for the same total power.

These results extending high fidelity operations and NDRO readout to larger arrays are essential for realizing high-repetition rate digital computation by enabling atoms to be re-used after measurements, while also allowing for postselection against loss. These techniques can be combined with atom sorting to allow reloading of atoms lost during operations [4,5], and can be adapted for applications

in quantum error correction for parallel readout of ancilla qubits [46,47] as required for fault-tolerant scaling.

The data presented in this work are available at [59].

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